

FQP6N40CF / FQPF6N40CF N-Channel QFET FRFET MOSFET 400 V, 6.0 A, 1.1 Ω

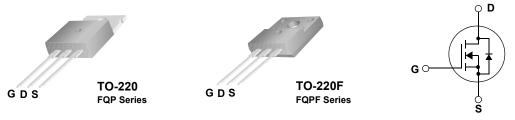
March 2013

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- 6.0 A, 400 V, $R_{DS(on)}$ = 1.1 Ω (Max) $@V_{GS}$ = 10 V, I_D = 3.0 A
- Low Gate Charge (Typ. 16 nC)
- Low Crss (Typ. 15 pF)
- 100% Avalanche Tested



Absolute Maximum Ratings

Symbol	Parameter			FQP6N40CF	FQPF6N40CF	Unit
V _{DSS}	Drain-Source Voltage		400		V	
I _D	Drain Current - Continuous (T _C = 25°C)		6	6*	Α	
		- Continuous (T _C = 100°C	C)	3.6	3.6*	Α
I _{DM}	Drain Current	- Pulsed (Note 1)		24	24*	Α
V _{GSS}	Gate-Source Voltage		± 30		V	
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	270		mJ
I _{AR}	Avalanche Current		(Note 1)	6		Α
E _{AR}	Repetitive Avalanche Energy (I		(Note 1)	73		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		20		V/ns	
P _D	Power Dissipation (T _C = 25°C)		73	38	W	
	- Derate above 25°C		0.58	0.3	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150		°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300		°C	

^{*} Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FQP6N40CF	FQPF6N40CF	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.71	3.31	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQP6N40CF	FQP6N40CF	TO-220	-	-	50
FQPF6N40CF	FQPF6N40CF	TO-220F	-	-	50

Electrical Characteristics T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charact	eristics		•			
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	400			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.54		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 400 V, V _{GS} = 0 V			1	μА
		V _{DS} = 320 V, T _C = 125°C			10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Charact	eristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 3 A		0.9	1.1	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 3 A (Note 4)		4.7		S
Dynamic Ch	naracteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		480	625	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		80	105	pF
C _{rss}	Reverse Transfer Capacitance	7		15	20	pF
Switching C	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 200 V, I _D = 6 A,		13	35	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		65	140	ns
t _{d(off)}	Turn-Off Delay Time	7		21	55	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		38	85	ns
Qg	Total Gate Charge	V _{DS} = 320 V, I _D = 6 A,		16	20	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		2.3		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		8.2		nC
Drain-Source	ce Diode Characteristics and Maximum R	atings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				6	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				24	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 6 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 6 A,		70		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)		0.12		μС

Notes:

- ${\bf 1.} \ {\bf Repetitive} \ {\bf Rating}: {\bf Pulse} \ {\bf width} \ {\bf limited} \ {\bf by} \ {\bf maximum} \ {\bf junction} \ {\bf temperature}$
- 2. L = 13.7mH, I $_{AS}$ = 6A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C
- 3. $I_{SD} \le 6A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting T_J = 25°C
- 4. Pulse Test : Pulse width $\leq 300 \mu s,$ Duty cycle $\leq 2\%$
- 5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

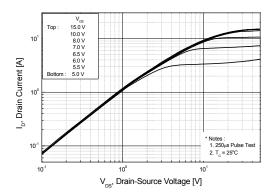


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

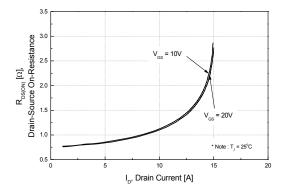


Figure 5. Capacitance Characteristics

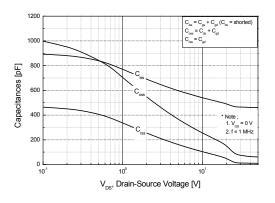


Figure 2. Transfer Characteristics

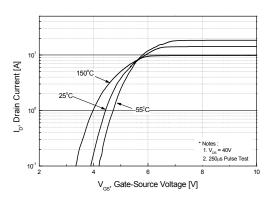


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

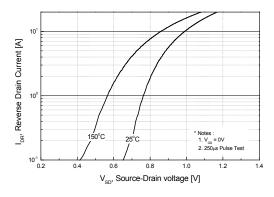
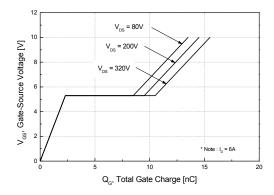


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

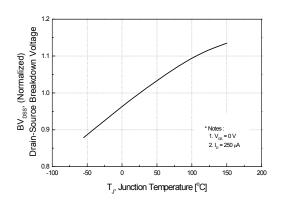


Figure 8. On-Resistance Variation vs. Temperature

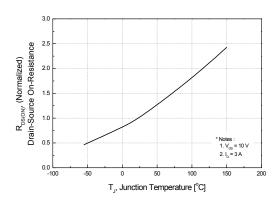


Figure 9-1. Maximum Safe Operating Area for FQP6N40CF

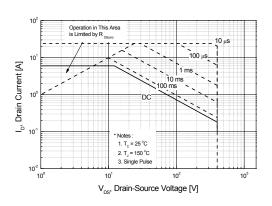


Figure 9-2. Maximum Safe Operating Area for FQPF6N40CF

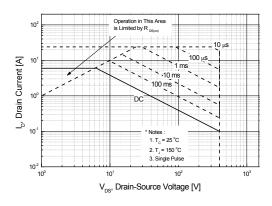
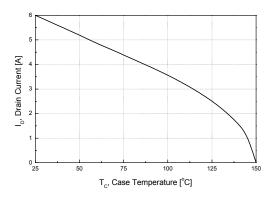


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 11-1. ransient Thermal Response Curve for FQP6N40CF

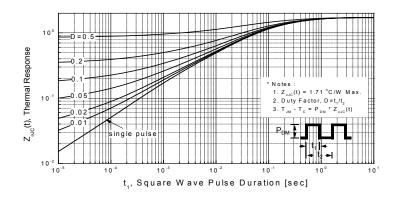
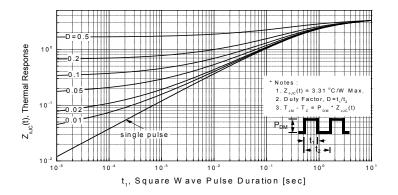
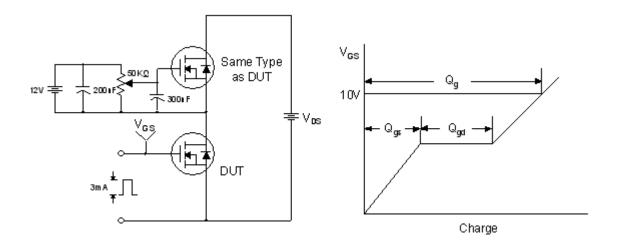


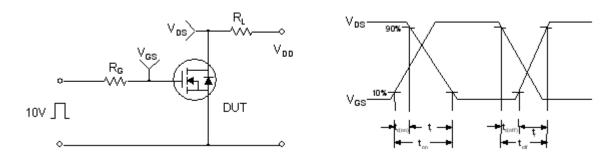
Figure 11-2. Transient Thermal Response Curve for FQPF6N40CF



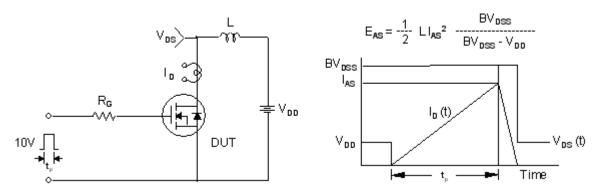
Gate Charge Test Circuit & Waveform



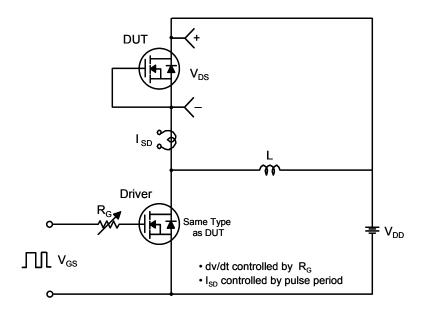
Resistive Switching Test Circuit & Waveforms

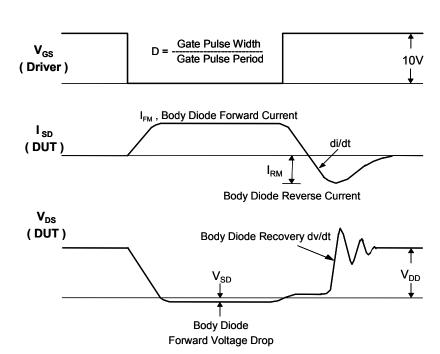


Unclamped Inductive Switching Test Circuit & Waveforms



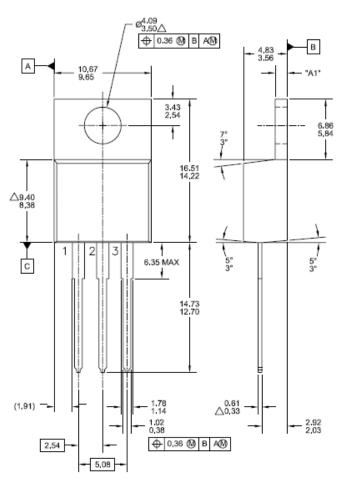
Peak Diode Recovery dv/dt Test Circuit & Waveforms

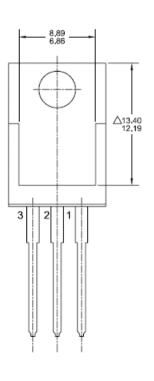


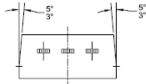


Mechanical Dimensions

TO-220



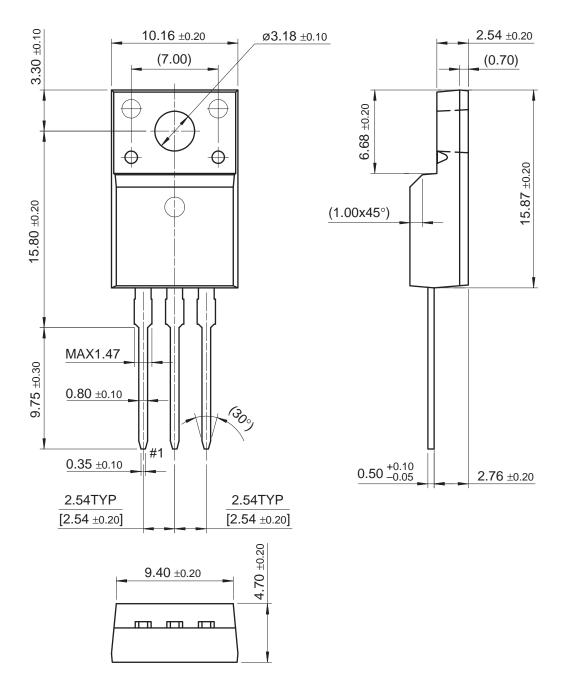




Dimensions in Millimeters

Mechanical Dimensions (Continued)

TO-220F



Dimensions in Millimeters





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

FPS™ AccuPower™ F-PFS™ AX-CAP® FRFET® BitSiC™ Global Power ResourceSM Build it Now™ Green Bridge™ Green FPS™ CorePLUS™

CorePOWER™ Green FPS™ e-Series™ $CROSSVOLT^{TM}$ Gmax™ GTO™ CTI ™ IntelliMAX™ Current Transfer Logic™

ISOPLANAR™ DFUXPFFD[®] Dual Cool™ Marking Small Speakers Sound Louder EcoSPARK® and Better™ MegaBuck™

EfficentMax™ ESBC™

Fairchild® Fairchild Semiconductor® FACT Quiet Series™ FACT® $\mathsf{FAST}^{\tiny{\circledR}}$

MicroPak™ MicroPak2™ MillerDrive™ MotionMax™ mWSaver™ OptoHiT™ OPTOLOGIC® FastvCore™ OPTOPLANAR® FETBench™

PowerTrench® PowerXS™

Programmable Active Droop™

OFET QSTM Quiet Series™ RapidConfigure™

> ng our world, 1mW/W/kW at a time™ SignalWise™ SmartMax™

SMART START™ Solutions for Your Success™

SPM[®] STEALTH™ SuperFET®

SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS® SyncFET™

Sync-Lock™

SYSTEM ®* TinyBoost™ TinyBuck™ TinyCalc™ TinyLogic[®] TINYOPTO™ TinyPower™ TinyPWM™ TinyWire™ TranSiC[®] TriFault Detect™ TRUECURRENT®* μSerDes™

UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™ VoltagePlus™

XS™

*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

MICROCOUPLER™

MicroFET™

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN WHICH COVERS THESE PRODUCTS

LIFE SUPPORT POLICY
FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE
EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS **Definition of Terms**

Datasheet Identification Product Status		Definition		
Advance Information Formative / In Design		Datasheet contains the design specifications for product development. Specification may change in any manner without notice.		
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.		
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.		
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.		

Rev. 164